X RAY POWDER DIFFRACTION DATA AND

STRUCTURAL REFINEMENT OF Er₃ Co₆Sn₅ ⁽¹⁾

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ABSTRACT The compound $Er_3 Co_6 Sn_5$ has been studied by means of X-ray powder diffraction technique and refined by Rietveld method. The compound $Er_3 Co_6 Sn_5$ has an orthorhombic $Dy_3 Co_6 Sn_5$ -type structure, space group I m m m (No.71), Z=2 and $D_x=9$.465 g/c m³. At room temperature, the lattice constants are a=4.2966(4) Å, b=12.2897(9) Å, c=9.6271(6) Å. The Rietveld structural refinement was performed and led to $R_{\rm wp}=0.196$ and $R_{\rm p}=0.153$. The figure of merit $F_{\rm N}$ for the X-ray powder diffraction data is $F_{30}=34.7(0.0090,96)$. The present structural refinement supports that Er(1), Er(2), E

Key words Er₃ Co₆ Sn₅ X-ray powder diffraction Rietveld structural refinement

1 INTRODUCTION

Rare metals and their compounds have outstanding properties and are paid increasing attention to. Numerous investigations in the ternary system rare earth-cobalt-tin have been made and novel compounds were discovered $^{[1,2]}$. Among them, $\rm Er_3Co_6Sn_5$ was reported that crystallizes in the orthorhombic structure, a new ternary ordered version of La₃ Al₁₁-type, with space group Immm (No. 71) $^{[1]}$. But the X-ray powder diffraction data for $\rm Er_3Co_6Sn_5$ was not reported at all. No structural refinement for this compound was found in literature. So the purpose of this work is to study its X-ray powder diffraction data and refine its crystal structure.

2 EXPERIMENTAL DETAILS

The alloy Er₃Co₆Sn₅ was prepared by arc

The alloy was brittle. The ingot was ground in an agate mortar and pestle to a particle size of less than 10 μ m. Powder diffraction data were collected with a Rigaku D/ max-RC diffractometer using a Cu target ($\lambda=1.540~60~\mbox{Å})$. The scan range was 10° to $120^{\circ}(2~\theta)$ with a step size of 0.02° and a count time of 2~s per step. A portion of powder sample was mixed with high purity Si powders as the internal standard for the determination of $\emph{d}\text{-}$ values. For relative intensity determination, another portion of the powder

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sample without internal standard was loaded into aluminum cavity specimen holder by the "Rear Loading" method [3]. The NIST SRM 1976 was used to calibrate the powder X-ray equipment for diffraction intensity. Some experimental details are the same as those in Ref. [4]. The crystal structural refinement of compound $\rm Er_3\,Co_6\,Sn_5$ has been carried out by Rietveld method from X-ray powder diffraction data.

3 RESULTS AND DISCUSSION

Table 1 shows the X-ray powder diffraction data for $\text{Er}_3\,\text{Co}_6\,\text{S}\,\text{n}_5$.

All of the X-ray diffraction patterns were indexed successfully on the basis of an orthorhombic structure by using TEROR program^[5]. The lattice parameters obtained by the least-squared method are a=4.2966(4) Å, b=12.2897(9) Å, c=9.6271(6) Å. The space group for the orthorhombic structure is Immm (No. 71). There are two formula units of Er₃Co₆Sn₅ in each unit cell. The Smith and Snyder figure of merit^[6] $F_{\rm N}$ is $F_{30}=34.7(0.0090,96)$. The index result is given in Table 1.

The Rietveld's powder diffraction profilefitting technique^[7,8] was used to analyze the Xray powder diffraction patterns of the compound Er₃Co₆Sn₅. The lattice constants obtained in this work and the atomic position parameters of Sm₃Co₆Sn₅^[1] were taken as starting values to refine the structural parameters of Er₃Co₆Sn₅. The atomic scattering factors were selected from the International Tables for X-ray Crystallography IV (1974)^[9]. The profile shape model was a Pearson VII type. The crystal structure was successfully refined by using the program DBWS-9006 PC[10]. The results of the Rietveld structural refinement are presented in Table 2, the refined atomic parameters are listed in Table 3. The refined lattice constants are a = 4.295 8(1) \mathring{A} , $b = 12.2902(2) \mathring{A}$, $c = 9.6267(1) \mathring{A}$ which are in good agreement with that obtained by a least-squared method. The pattern R-factor $R_{\rm p}$ and the weighted pattern R-factor R_{wp} are $R_p =$ 0.153 and $R_{wp} = 0.196$, respectively.

Table 1 X-ray powder diffraction data for Er₃Co₆Sn₅

		5 - 10 3	
$2 \theta_{\rm exp} / (^{\circ})$	I/I_0	$d_{\mathrm{exp}}/$ Å	hkl
11 .665	2	7 .58	011
14.414	2	6 .1 40	202
8.747	8	3 .1 03	112
30 .116	56	2 .965	130
34 .618	21	2.589	042
34.854	38	2.572	103
35 .510	100	2.526	132
37 .901	31	2.372	1 2 3
40 .21 2	7	2 .240 8	024
42.024	32	2 .1 48 3	200
42 .313	32	2.1343	150
43 .702	1 4	2 .069 6	114
44 .1 56	22	2 .049 4	060
46 .006	6	1 .971 2	1 43
46 .520	25	1 .950 6	152
48 .259	6	1 .8843	062
55 .517	6	1 .653 9	242
57 .445	15	1 .602 9	204
59 .557	3	1 .551 0	224
60 .021	7	1 .5401	172
62 .606	10	1 .482 6	260
64 .448	7	1 .444 6	253
66 .160	22	1 .411 3	136
69 .471	5	1 .351 9	330
71 .471	11	1 .3189	183
72 .179	6	1 .307 7	303
72 .578	11	1 .301 5	190
73 .628	5	1 .285 5	206
74 .051	5	1 .279 2	323
75 .1 43	8	1 .263 3	066
75 .61 4	5	1 .2566	093
87 .415	4	1 .1148	138
90 .081	7	1 .088 6	266
90 .526	5	1 .0844	293
96 .363	3	1 .033 6	336
99 .321	4	1 .0106	196
101.347	2	0 .995 8	383
102.415	4	0 .988 3	433
104.350	2	0 .975 2	2 1 0 4

Table 2 Crystallographic data and Rietveld structural refinement for Er₃Co₆Sn₅

	101 213 006 0113	
Space group	Immm (No.71)	
Cell Parameters/ Å	a = 4.2966(4), b = 12.2897(9), c = 9.6271(6)	
Volume of unit cell/ \mathring{A}^3	508 .35	
Number of formula unit Z	2	
Radiation	$Cu K_{\alpha l}$	
2 θ / (°)	10.00 ~ 120.00	
Step scan incre ment $\Delta 2 \theta / (^{\circ})$	0.02	
Count time/(s•step-1)	2	
Number of refined parameters	21	
Number of reflections	482	
Reliability factors(R-factor)	$R_{\rm P}^* = 0.153$, $R_{\rm WP}^* = 0.196$	

*
$$R_{\rm P} = \sum_{i} | Y_{\rm oi} - Y_{\rm c}_{i} | / \sum_{i} Y_{\rm oi};$$

 $R_{\rm WP} = [\sum_{i} W_{i} (Y_{\rm oi} - Y_{\rm ci})^{2} / \sum_{i} W_{i} Y_{\rm oi}^{2}]^{1/2}$

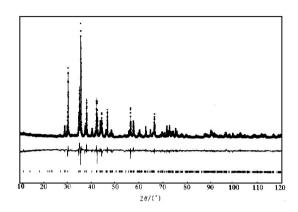
To make a comparison, pseudo Voigt (pV) and Modified Thompson Cox-Hastings pseudo Voigt (Mod-TCH pV) profile functions were used in this refinement, too. The pattern R-factors from pV and Mod-TCH pV profile functions are $R_{\rm p}=0.157$ and $R_{\rm p}=0.155$, respectively.

Table 3 Refined atomic parameters for $Er_3Co_6Sn_5$

Atom	Site	х	у	z	N
Er(1)	2 a	0	0	0	2
Er(2)	4 g	0	0.3151(3)	0	4
Co(1)	4 j	0	1 / 2	0.1959(9)	4
Co(2)	8 l	0	0.1078(5)	0.2742(7)	8
Sn(1)	2 c	0	0	1 / 2	2
Sn(2)	8 l	0	0.3237(3)	0.3416(4)	8

The present structural refinement supports that the atomic positions of $Er_3 Co_6 Sn_5$ are similar to those of $Sm_3 Co_6 Sn_5$. In the structure of $Er_3 Co_6 Sn_5$, Er(1) and Er(2) atoms occupy the 2 a and 4 g positions, Co(1) and Co(2) atoms occupy the 4 j and 8 l positions, Sn(1) and Sn(1)

(2) atoms are at the 2 c and 8 l positions, respectively. Fig.1 shows the difference between the experimental and calculated patterns of X-ray diffraction patterns of $Er_3Co_6Sn_5$.



 $\begin{aligned} \textbf{Fig.1} & \quad \text{X-ray diffraction patterns for Er_3Co$_6$Sn$_5} \\ & \quad \bullet - \text{Experimental pattern} \ ; \end{aligned}$

Solid line — Calculated pattern; | — Possible positions of Bragg reflections; Middle curves — Difference between experimental and calculated patterns

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